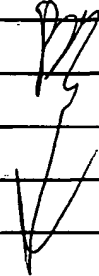
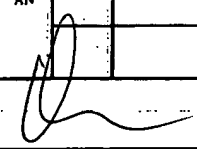
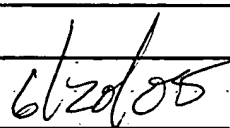


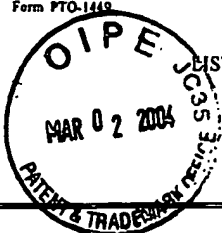
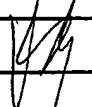
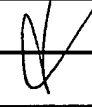
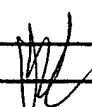
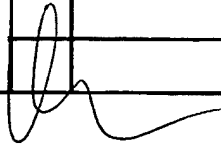
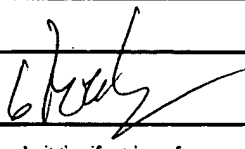
Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2434		PRIORITY SERIAL NO. 10424340 101697013	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Micron Technology, Inc.			
					PRIORITY FILING DATE 4/11/2002		PRIORITY GROUP 1762	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
↓	AA	5,951,887	9/14/99	MABUCHI et al.	↓	↓	↓	
	AB	6,446,573	9/10/02	HIRAYAMA et al.				
	AC	5,988,104	11/23/99	NAMBU				
	AD	5,788,778	8/4/98	SHANG et al.				
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	AH	5,545,258	8/13/96	KATAYAMA et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AI							
	AJ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AK							
	AL							
	AM							
	AN							
	AO							
EXAMINER				DATE CONSIDERED				
↓				4/20/02				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				PRIORITY FILING DATE 4/11/2002		PRIORITY GROUP 1262 1762	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,527,908	3/4/2003	KANETSUKI et al.			
	AB	6,158,383	12/12/2000	WATANABE et al.			
	AC	5,134,965	8/4/1992	TOKUDA et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK						
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	AM						
	AN						
EXAMINER 				DATE CONSIDERED 			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Craig M. Carpenter et al.				
				FILING DATE October 30, 2003		GROUP NO. 4334-1762		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,749,966	05/98	Shates				
	AB	5,698,036	12/97	Ishii et al.				
	AC	6,040,021	03/00	Miyamoto				
	AD							
	AE							
	AF							
	AG							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AH	EP 1 115 147 A1	07/01	EPO				
	AI	0 520 832 A1	12/92	EPO				
	AJ	US-03/09913	03/03	PCT Search Report				
	AK			NOT A PUBLICATION				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AL							
	AM							
	AN							
	AO							
	AP							
EXAMINER				DATE CONSIDERED				
								
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